

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application)	<u>PATENT APPLICATION</u>
)	
Inventors:	Frederick Ware, et al.)
)	
Application No.:	10/768,443)
)	Art Unit: 2829
Filed Date:	Jan. 30, 2004)
)	Examiner: Nguyen, T.
Title: METHOD AND APPARATUS FOR TEST)	Customer No.: 38456
CHARACTERIZATION OF SEMICONDUCTOR)	
COMPONENTS)	
)	

RESPONSE TO OFFICE ACTION UNDER 37 C.F.R. §1.111

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This RESPONSE is in reply to the outstanding Office action.

AMENDMENTS to the CLAIMS begin on Page 2 of this RESPONSE.

REMARKS begin on Page 28 of this RESPONSE.